

Electrical and optical characterization of graphene oxide and reduced graphene oxide thin films

Supplementary materials

SEM images of GO and RGO films were acquired on Si/SiO₂ substrates to improve GO visibility.

SEM analysis was accomplished with a FEI Quanta FEG 400 F eSEM microscope (Eindhoven, The Netherlands).

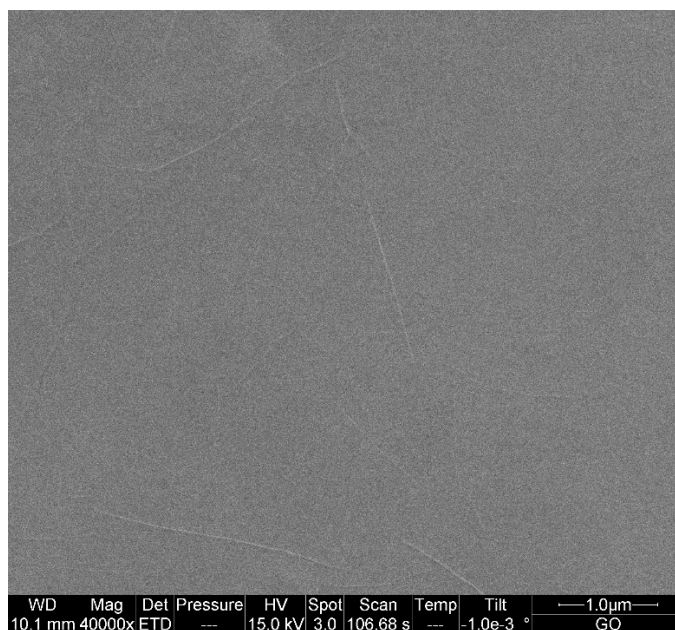


Figure S1: Scanning electron microscopy image of GO films on Si/SiO₂ substrates.

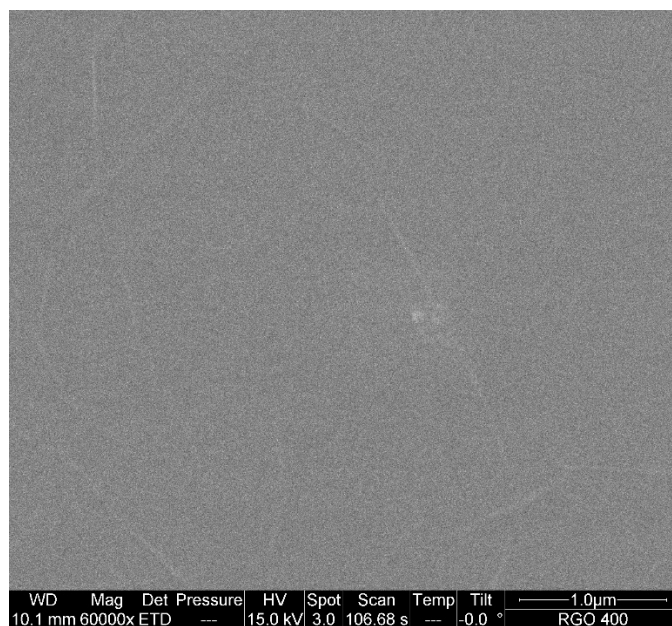


Figure S2: Scanning electron microscopy image of RGO films on Si/SiO₂ substrates.

Figure S1 shows that the GO film covers the whole surface uniformly. The topology of the samples does not change upon heating, as it is visible in Figure S2.